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Journal of Quality Technology

Volume 10, Numbers 1-4, 1978

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Editorial Collaborators

In addition to the fine work of the editorial review board of the *Journal of Quality Technology*, the individuals whose names appear below have also made significant contributions to the journal by refereeing submitted manuscripts. On behalf of *JQT* and *ASQC*, I wish to publicly thank and acknowledge these referees for their service.

John S. Ramberg
Editor

B. Abraham
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Hunter, William G., and Kartha, C. P., "Determining the Most Profitable Target Value for a Production Process," Vol. 9, No. 4, October 1977, pp. 176-181.

The horizontal logarithmic scale in Figure 2 was inadvertently drawn with the tick marks incorrectly spaced arithmetically. However, a larger and more detailed figure for the same purpose of determining δ^*/σ from $g\sigma/(a - r)$ appears in TECHNICAL AIDS, Vol. 10, No. 2, April 1978, p. 89.

Olsson, D. M., "Randomized Complete Block Design," Vol. 10, No. 1, January 1978, pp. 40-41.

The computer output for the example given in this article was inadvertently omitted and appears here.

ANOVA* RANDOMIZED COMPLETE BLOCK DESIGN

BENNETT + FRANKLIN, STAT. ANAL. IN CHEMISTRY... PP. 377-379

NO. OF TREATMENTS= 3, NO. OF BLOCKS= 10, GRAND AVERAGE= 5.94000

SOURCE OF VARIATION	SUM OF SQUARES	DEGREES OF FREEDOM	MEAN SQUARE	F RATIO
DUE TO TREATMENTS	0.024000	2	0.012000	1.584
DUE TO BLOCKS	164.372004	9	18.263556	2417.272
RESIDUAL	0.135996	18	0.007555	
TOTAL(ADJUSTED)	164.532001	29		

PROBABILITY OF EXCEEDING THE ABOVE TREAT F RATIO IS APPROX. 0.231

PROBABILITY OF EXCEEDING THE ABOVE BLOCK F RATIO IS APPROX. 0.000

(ANALYSIS IF TREATMENTS ARE FIXED EFFECTS)

RESIDUAL STD. DEVIATION	STD. DEVIATION OF TREAT. AVERAGE
0.086922	0.027487

TREAT NO.	AVERAGE
1	5.900000
2	5.960000
3	5.960000

BLOCK NO.	AVERAGE
1	10.100000
2	4.850000
3	3.066667
4	3.100000
5	7.800000
6	8.266667
7	7.800000
8	6.100000
9	5.000000
10	3.366667

(ANALYSIS IF RANDOM EFFECTS MODEL)

RESIDUAL VARIANCE COMPONENT= 0.007555
TREATMENT VARIANCE COMPONENT= 0.000444
BLOCK COMPONENT OF VARIANCE= 0.085334

TREAT	BLOCK	OBSERVED RESPONSE	ESTIMATED RESPONSE	RESIDUAL
1	1	10.100000	10.060000	0.040000
1	2	4.700000	4.760000	-0.060000
1	3	3.100000	3.026667	0.073333
1	4	3.000000	3.060000	-0.060000
1	5	7.800000	7.760000	0.040000
1	6	8.200000	8.226667	-0.026667
1	7	7.800000	7.760000	0.040000
1	8	6.300000	6.060000	-0.060000
1	9	4.900000	4.960000	-0.060000
1	10	3.400000	3.326667	0.073333
2	1	10.000000	10.120000	-0.120000
2	2	4.900000	4.820000	0.080000
2	3	3.100000	3.086667	0.013333
2	4	3.200000	3.120000	0.080000
2	5	7.900000	7.820000	-0.020000
2	6	8.400000	8.286667	-0.086667
2	7	7.700000	7.820000	-0.120000
2	8	6.200000	6.120000	0.080000
2	9	5.100000	5.020000	0.080000
2	10	3.400000	3.386667	0.013333
3	1	10.200000	10.120000	0.080000
3	2	4.900000	4.820000	-0.020000
3	3	3.000000	3.086667	-0.086667
3	4	3.100000	3.120000	-0.020000
3	5	7.800000	7.820000	-0.020000
3	6	8.400000	8.286667	0.113333
3	7	7.900000	7.820000	0.080000
3	8	6.100000	6.120000	-0.020000
3	9	5.000000	5.020000	-0.020000
3	10	3.300000	3.386667	-0.086667

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H. Alan Lasater, 1971-1973 Lawrence D. Romboski, 1974-1976 John S. Ramberg, 1977-1979

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The subject index was prepared by Dr. George E. Policello II of the Department of Statistics, The Ohio State University. It is a pleasure to acknowledge his careful and exhaustive work on this project. The other indexes were prepared in my office with the careful and diligent help of Mrs. Sandra J. Wright. The index of selected figures and tables is designed to provide for the retrieval of charts, graphs, nomographs, tables and the like that are potentially useful enough to deserve special attention.

LLOYD S. NELSON

August 1978

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